

Search Notes

Application/Control No.

10/775,799

Examiner

Khanh V. Nguyen

Applicant(s)/Patent under
Reexamination

GURVICH ET AL.

Art Unit

2817

SEARCHED

Class	Subclass	Date	Examiner
330	149, first 500 patents @ad<="20 030214"	11/23/05	NKV
330	151 and detect\$3	12/29/05	NKV

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner
See Search History Printout		11/23/05	NKV

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
EAST (US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB_	11/23/05	NKV
IEEE	11/21/05	NKV